


<b>Search Notes</b>  	<b>Application/Control No.</b>  10684445	<b>Applicant(s)/Patent Under Reexamination</b>  BAIK, KWANG JUN
	<b>Examiner</b>  Lamb, Christopher R	<b>Art Unit</b>  2627

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Consulted SPE Wayne Young regarding field of search for amended claims	11/17/06	CRL
Consulted SPE Wayne Young regarding allowable subject matter	11/20/06	CRL
Searched foreign databases at request of SPE William Korzuch	11/27/06	CRL

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
-	See EAST Search	11/21/06	CRL